

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SHIN ET AL.	
		Examiner Linh T. Nguyen	Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0027844	03-2002	Furuhashi et al.	369/44.37
*	B	US-2003/0179680	09-2003	Park et al.	369/112.04
*	C	US-2002/0196726	12-2002	Takeda, Tadashi	369/112.04
*	D	US-5,029,154	07-1991	Sumi et al.	369/44.23
*	E	US-2002/0097660	07-2002	Komma et al.	369/112.04
*	F	US-6,130,872	10-2000	Sugiura et al.	369/112.04
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.